

N-channel 100 V, 2.85 mΩ typ., 110 A STripFET™ F7 Power MOSFET in a TO-220 package

Datasheet - production data

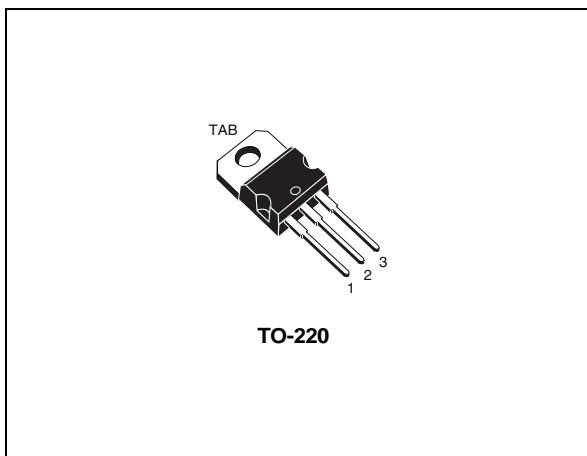
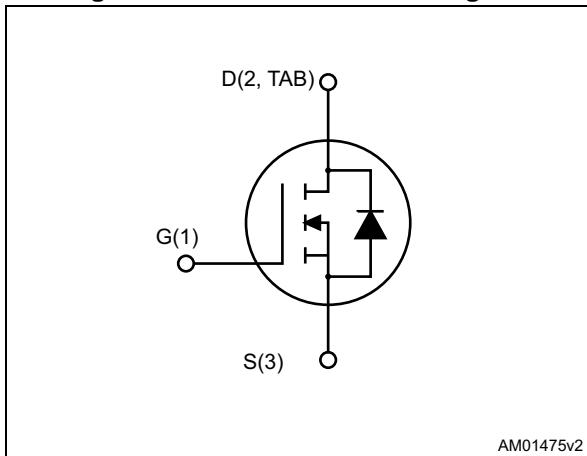


Figure 1. Internal schematic diagram



Features

Order code	V_{DS}	$R_{DS(on)}^{\text{max.}}$	I_D
STP240N10F7	100 V	3.2 mΩ	110 A

- Ultra low on-resistance
- 100% avalanche tested

Applications

- High current switching applications

Description

This N-channel Power MOSFET utilizes the STripFET™ F7 technology with an enhanced trench gate structure that results in very low on-state resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Table 1. Device summary

Order code	Marking	Package	Packaging
STP240N10F7	240N10F7	TO-220	Tube

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	100	V
V_{GS}	Gate-source voltage	± 20	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	110	A
$I_D^{(1)}$	Drain current (continuous) at $T_C=100^\circ\text{C}$	110	A
$I_{DM}^{(2)}$	Drain current (pulsed)	440	A
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	300	W
$E_{AS}^{(3)}$	Single pulse avalanche energy	500	mJ
T_j	Operating junction temperature	- 55 to 175	$^\circ\text{C}$
T_{stg}	Storage temperature		

1. Current limited by package.
2. Pulse width limited by safe operating area.
3. Starting $T_j=25^\circ\text{C}$, $I_d=45\text{A}$, $V_{dd}=50\text{V}$

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	0.5	$^\circ\text{C/W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5	$^\circ\text{C/W}$

2 Electrical characteristics

($T_{CASE} = 25^\circ\text{C}$ unless otherwise specified).

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0$, $I_D = 250 \mu\text{A}$	100			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0$, $V_{DS} = 100 \text{ V}$			1	μA
		$V_{GS} = 0$, $V_{DS} = 100 \text{ V}$, $T_C = 125^\circ\text{C}$			100	μA
I_{GSS}	Gate body leakage current	$V_{DS} = 0$, $V_{GS} = +20 \text{ V}$			100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	2.5		4.5	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}$, $I_D = 60 \text{ A}$		2.85	3.2	$\text{m}\Omega$

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{GS} = 0$, $V_{DS} = 25 \text{ V}$, $f = 1 \text{ MHz}$	-	11550	-	pF
C_{oss}	Output capacitance		-	2950	-	pF
C_{rss}	Reverse transfer capacitance		-	217	-	pF
Q_g	Total gate charge	$V_{DD} = 50 \text{ V}$, $I_D = 110 \text{ A}$, $V_{GS} = 10 \text{ V}$	-	160	-	nC
Q_{gs}	Gate-source charge		-	48	-	nC
Q_{gd}	Gate-drain charge		-	38	-	nC

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(\text{on})}$	Turn-on delay time	$V_{DD} = 50 \text{ V}$, $I_D = 90 \text{ A}$ $R_G = 4.7 \Omega$ $V_{GS} = 10 \text{ V}$	-	49	-	ns
t_r	Rise time		-	139	-	ns
$t_{d(\text{off})}$	Turn-off delay time		-	110	-	ns
t_f						

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		110	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		440	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS}=0$, $I_{SD}=110$ A	-		1.2	V
t_{rr}	Reverse recovery time	$I_{SD}=110$ A, $dI/dt = 100$ A/ μ s, $V_{DD}=80$ V, $T_j=150^\circ\text{C}$	-	108		ns
Q_{rr}	Reverse recovery charge		-	315		nC
I_{RRM}	Reverse recovery current		-	5.8		A

1. Pulse width limited by safe operating area.

2. Pulse duration = 300 μ s, duty cycle 1.5%